

Abstracts

Statistical Modeling of GaAs MESFETs

J.W. Bandler, R.M. Biernacki, S.H. Chen, J. Song, S. Ye and Q.J. Zhang. "Statistical Modeling of GaAs MESFETs." 1991 MTT-S International Microwave Symposium Digest 91.1 (1991 Vol. I [MWSYM]): 87-90.

This paper contrasts the statistical extraction of GaAs MESFET equivalent circuit model parameters and physical model parameters from wafer measurements. We observe that the Materka and Kacprzak model based on equivalent circuit parameters provides a better match for individual devices, but the Ladbroke model based on physical parameters provides a better estimate of device statistics.

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